

Search Notes

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10/665,440

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent under
Reexamination

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Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
429	12,34,46	11/13/2006	DWY
29	623.1	11/13/2006	DWY

INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST	11/13/2006	DWY